

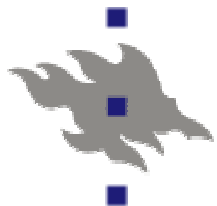


ATOMIC LAYER DEPOSITION FOR PHOTONIC CRYSTAL DEVICES

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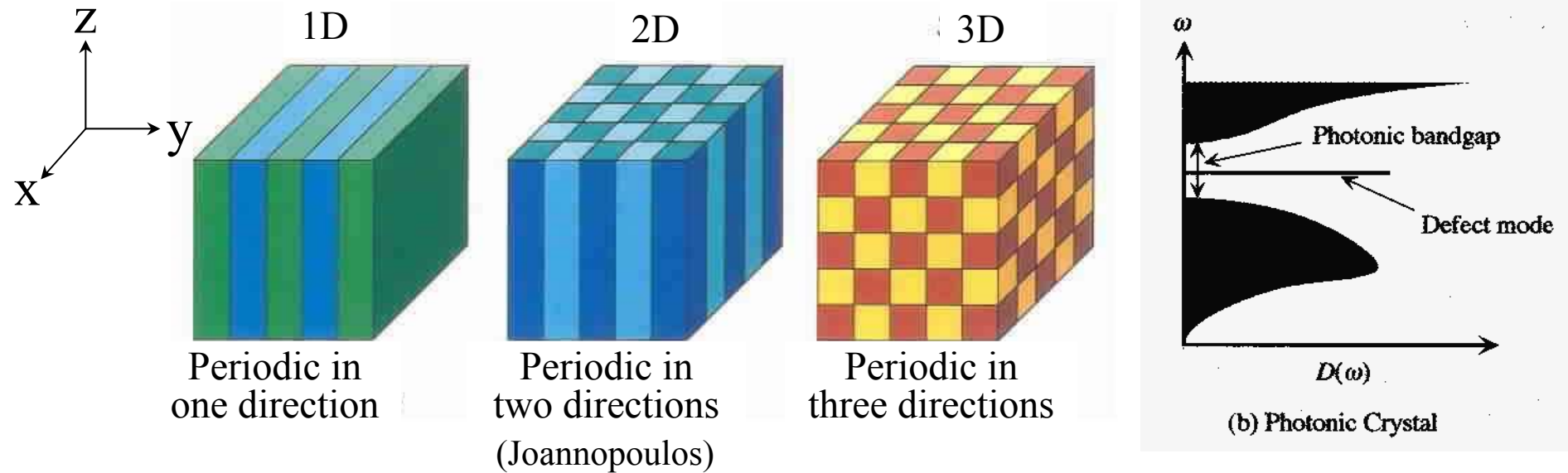
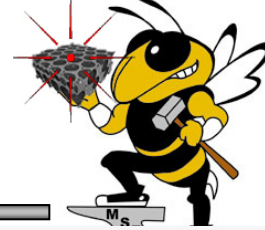


Outline



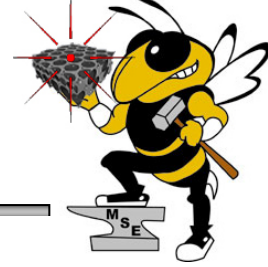
- Introduction to Photonic Crystals
- Opals
- Inverse Opal
 - Requirements for Photonic Band Gaps: high filling fraction, smooth, conformal, high refractive index
- Infiltration using ALD
 - Meets above requirements
- Results: ZnS:Mn, TiO₂, Multi-layers
- Summary

Photonic Crystals

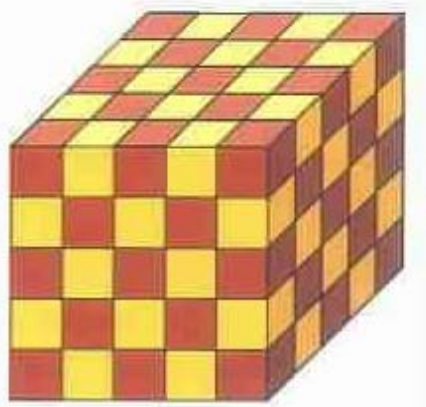


- Photonic Crystal – periodic modulation of dielectric constant
- Exhibits a “Photonic Band Gap” (PBG) where propagation of a range of photon energies is forbidden.
- For visible wavelengths, periodicity on order of 150 – 500 nm.
- Introduction of “dielectric defects” yield modes within the PBG.
- Luminescent 2D & 3D PC structures offer the potential for controlling wavelength, efficiency, time response and threshold properties (phosphors, displays, solid state lighting, etc.).

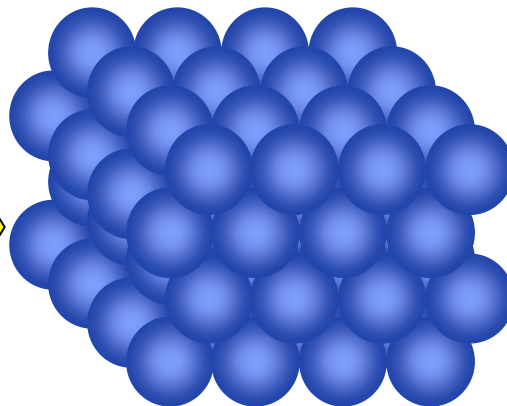
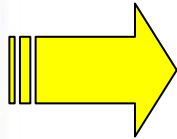
Real Photonic Crystals: Opals & Inverse Opals



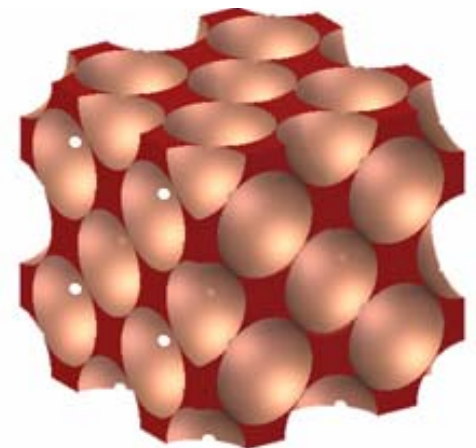
- For 3D PC's: “top-down” approaches are difficult.
 - “Bottom-up” approach: self-assembly
- Most common 3D photonic crystal is the opal.
 - Close-packed silica spheres in air
- Opal is used as a template to create an inverse opal.
 - Close-packed air spheres in a dielectric material



3D-PC



Opal
26% air

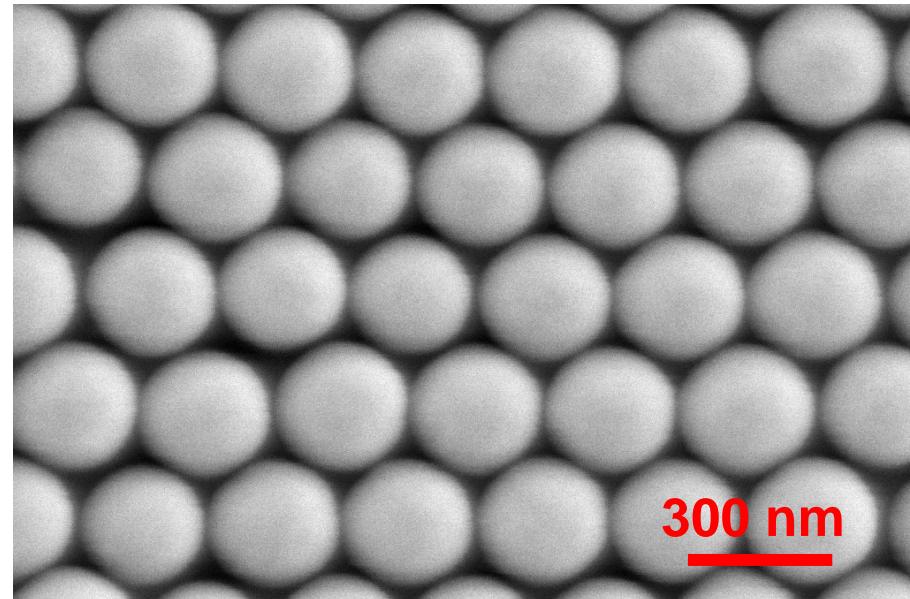
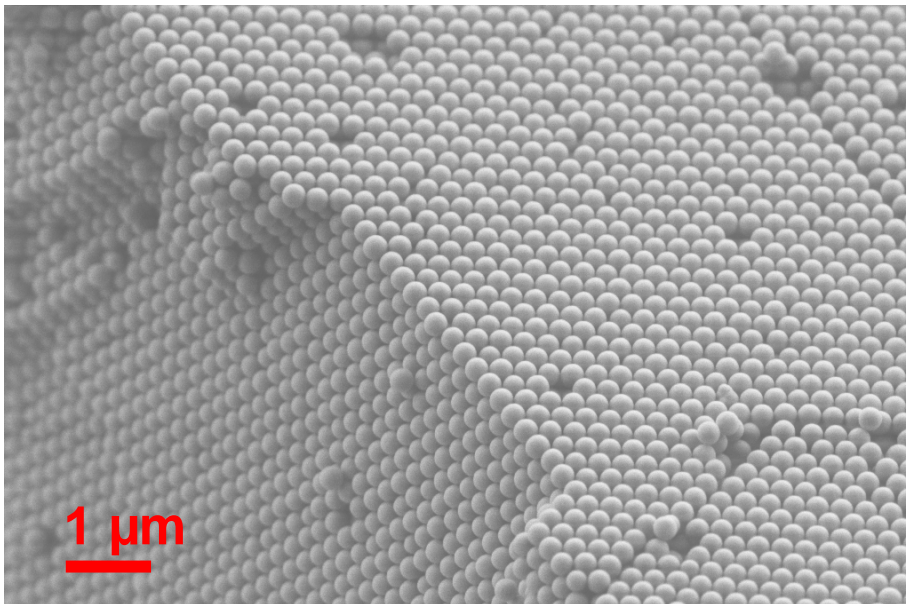


Inverse Opal
74% air for high
dielectric contrast

SiO₂ Opal Films



- Opal films are polycrystalline, 10 μm thick, FCC films with the (111) planes oriented parallel to the surface.
- For visible spectrum, lattice constant $\sim 140 - 500$ nm.



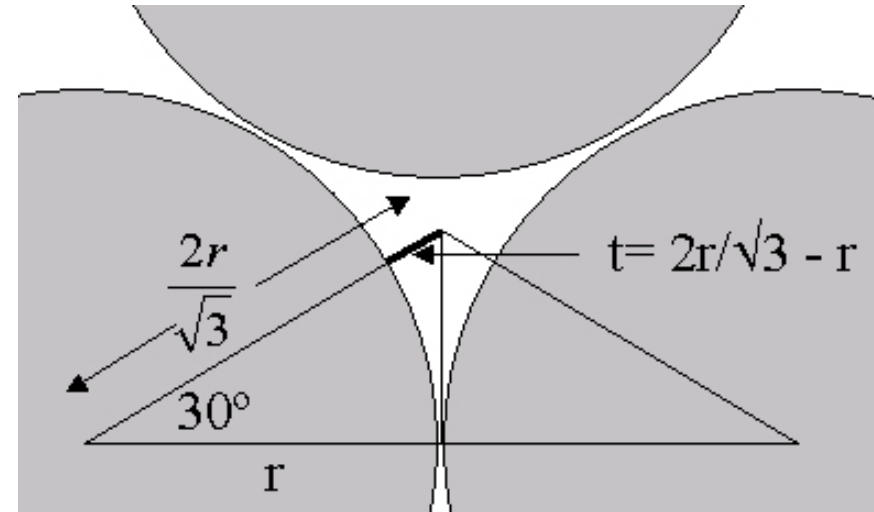
Challenge: growth of uniform films within a dense, highly porous, high surface-area, FCC matrix

Opal Infiltration: Growth Issues

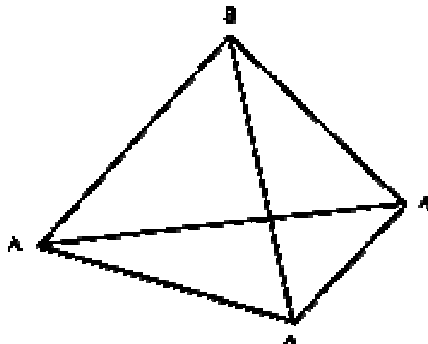


Geometrical Constraints

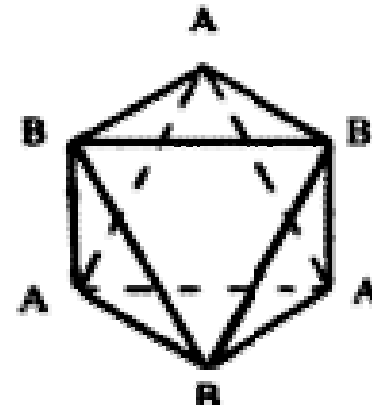
- Narrowest pathway (bottleneck) into opal is through (111) planes.
- Consideration of geometry predicts pore closure at 7.75% of sphere diameter.
- Monte Carlo simulations show this is $\sim 86\%$ infiltration of voids.



- Tetrahedral void size is $0.46 \times r_{\text{sphere}} \sim 32\text{--}115 \text{ nm}$.



- Octahedral void size is $0.82 \times r_{\text{sphere}} \sim 57\text{--}205 \text{ nm}$.



Opal Films: Growth Issues

Increased Surface Area



- Surface area of opal film is much larger than an equivalent planar area:

$$\frac{A_{\text{opal}}}{A_{\text{film}}} = \frac{0.74 \times l \times w \times t}{4/3\pi r^3} \times \frac{4\pi r^2}{l \times w} = \frac{2.22t}{r}$$

- For a 10 μm thick opal film with 200 nm diameter spheres:

$$A_{\text{opal}}/A_{\text{film}} = 222$$

Opal Infiltration: Requirements

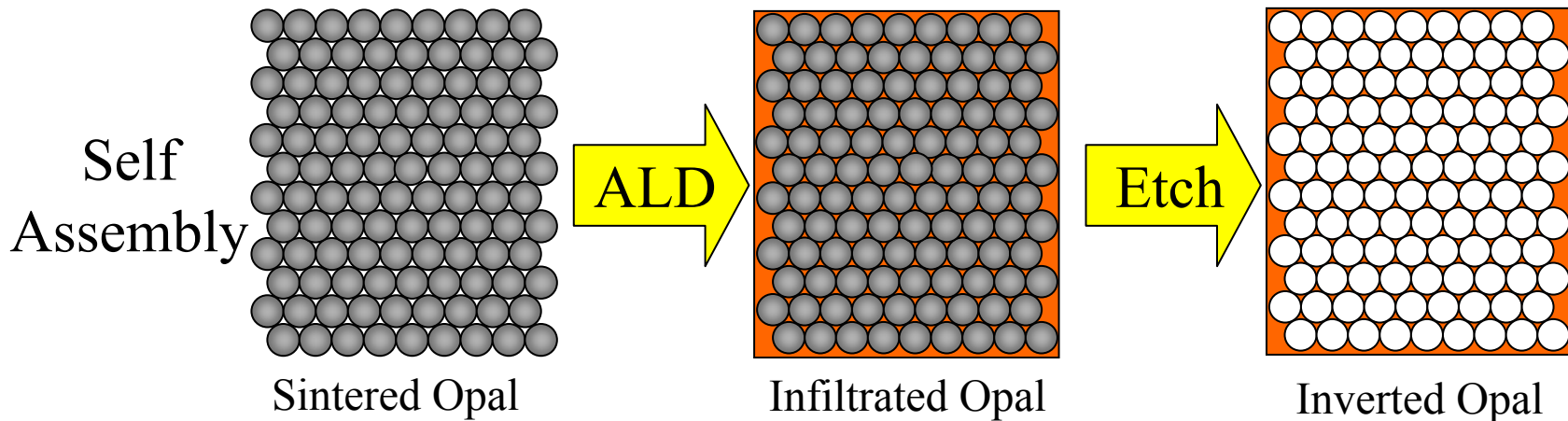


- Uniform Infiltration
 - Material must be distributed uniformly throughout the opal
- Controlled Filling Fraction
 - Must be able to precisely control the void space filling
- Conformal and Smooth Surfaces
 - Creates lower porosity infiltrations
 - Creates air pockets at the center of the opal voids, enhancing the PBG
- High Refractive Index, Transparent, & Luminescent Materials
 - For a full PBG, the refractive index contrast (with air) must be > 2.8
- **ALD is the only technique to meet all of these requirements**

Inverse Opal: Fabrication



- Self-assembled silica opal template
 - 10 μm thick FCC polycrystalline film, (111) oriented.
- Infiltration of opal with high index materials
 - ZnS:Mn $n \sim 2.5$ @ 425 nm (directional PBG)
 - TiO_2 (rutile) $n_{\text{avg}} \sim 3.08$ @ 425 nm (omni-directional PBG)



Opal Infiltration: Atomic Layer Deposition



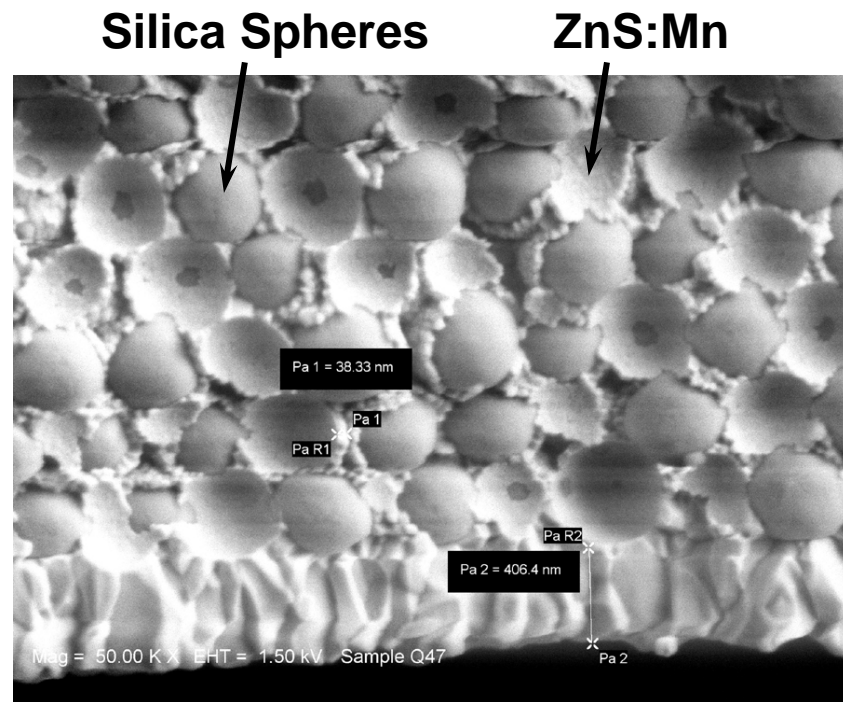
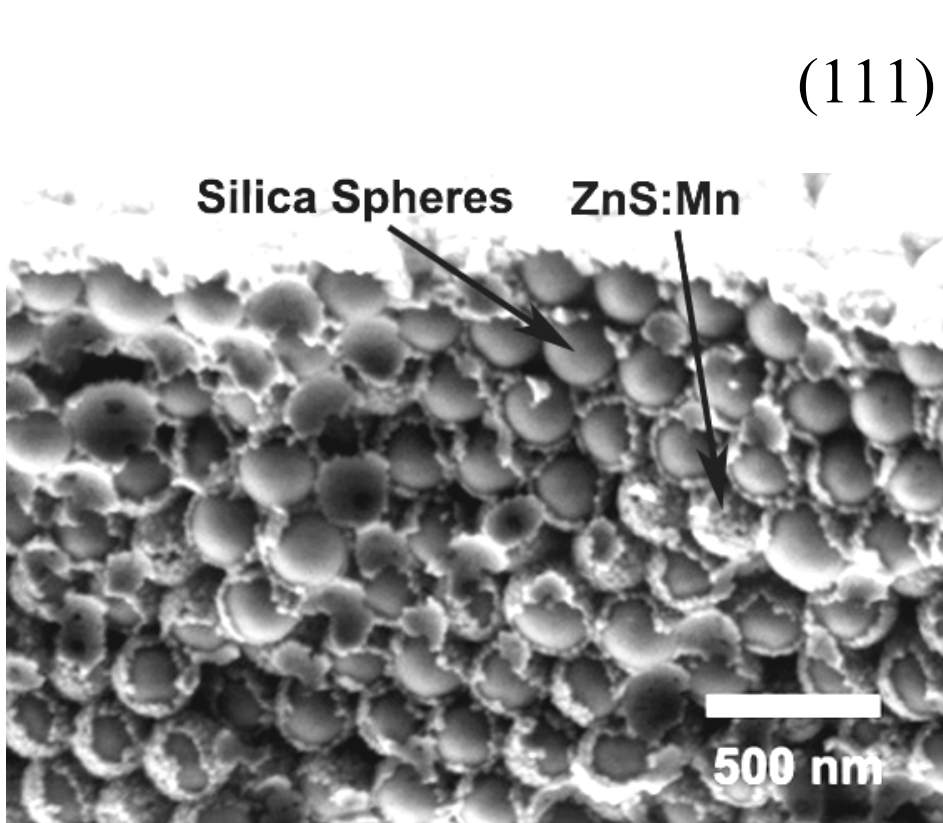
- ZnS:Mn Infiltrations

- Initial conditions: $\text{ZnCl}_2/\text{H}_2\text{S}$ - 660ms/660ms, N_2 purge - 550ms
- **Optimum conditions: $\text{ZnCl}_2/\text{H}_2\text{S}$ – 2s/2s, N_2 purge - 2s**
- 10s MnCl_2 pulse every 100th cycle
- Performed at US Army Research Laboratory (ARL) using a Microchemistry F-120

- TiO_2 Infiltrations

- Initial conditions: $\text{TiCl}_4/\text{H}_2\text{O}$ - 1s/1s, N_2 purge - 1s
- **Optimum conditions: $\text{TiCl}_4/\text{H}_2\text{O}$ - 4s/4s, N_2 purge - 10s**
- Performed at Georgia Tech using a custom built hot-wall, flow-style reactor

ALD of ZnS:Mn: Scanning Electron Microscopy



220 nm infiltrated opal

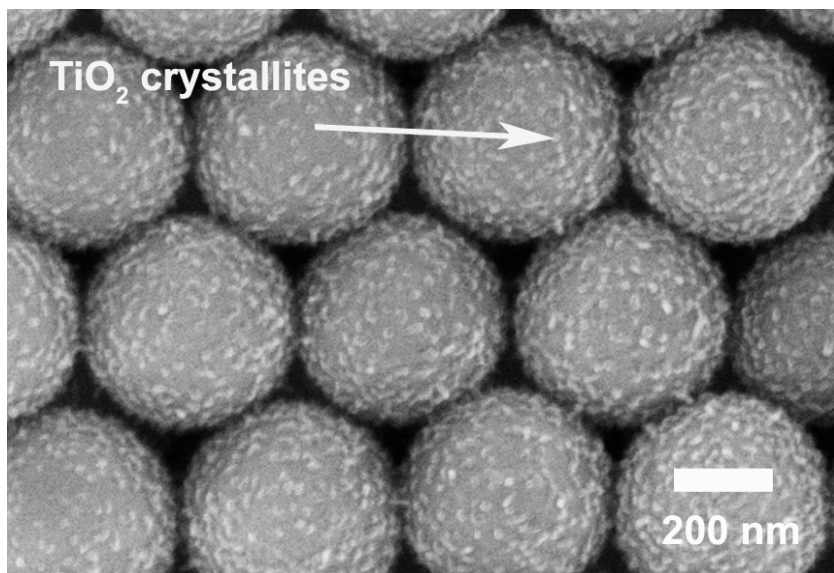
460 nm infiltrated opal

Growth Conditions: 500°C, ZnCl₂ – 660 ms, H₂S – 660 ms

ALD of TiO_2

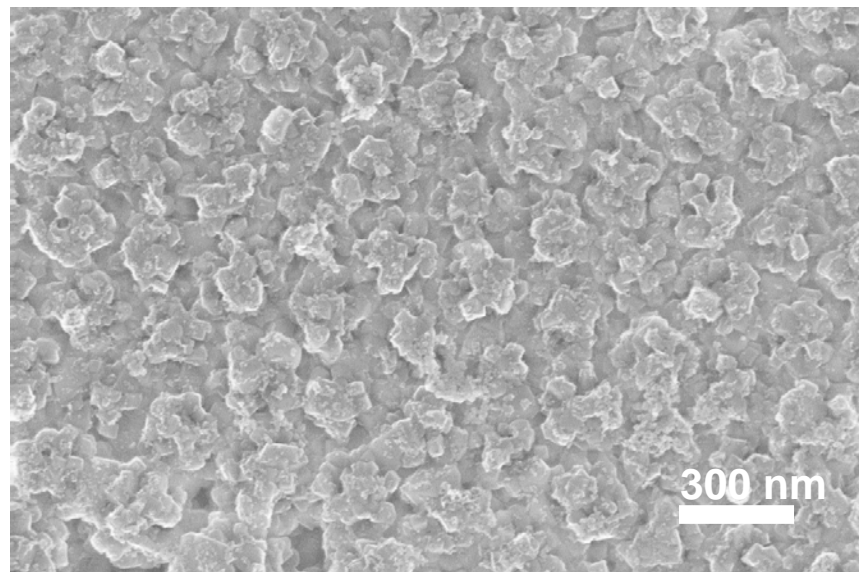


(111) \odot



433 nm opal with TiO_2 crystallites deposited at 600°C.

Polycrystalline TiO_2 grown at high temperatures produces very rough surface coatings.



224 nm opal with TiO_2 deposited at 500°C.

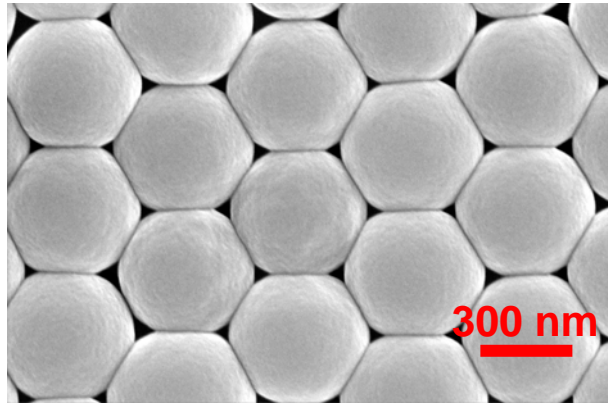
The opal structure is lost at the outer surface for complete TiO_2 infiltrations at high temperatures.

ALD of TiO_2 at 100°C

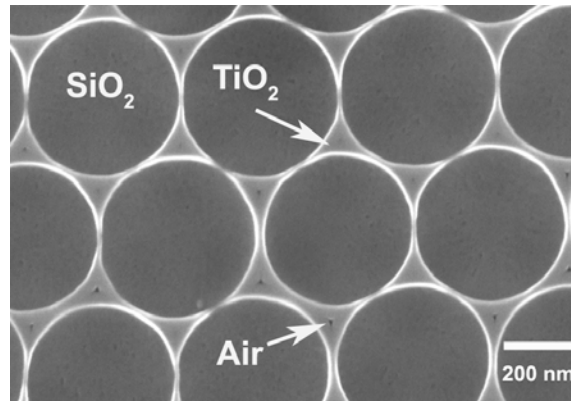


(111) \odot

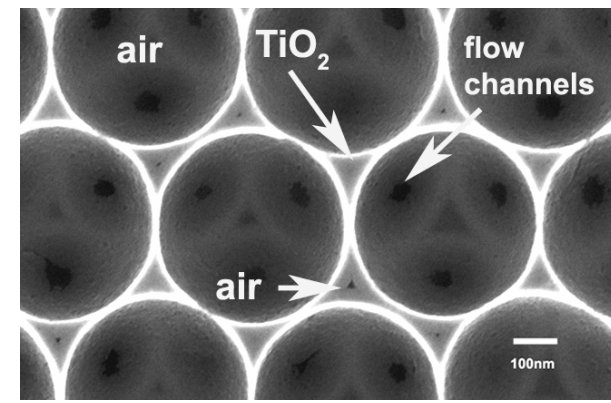
Cross-sections



433 nm opal infiltrated
with 20 nm of TiO_2

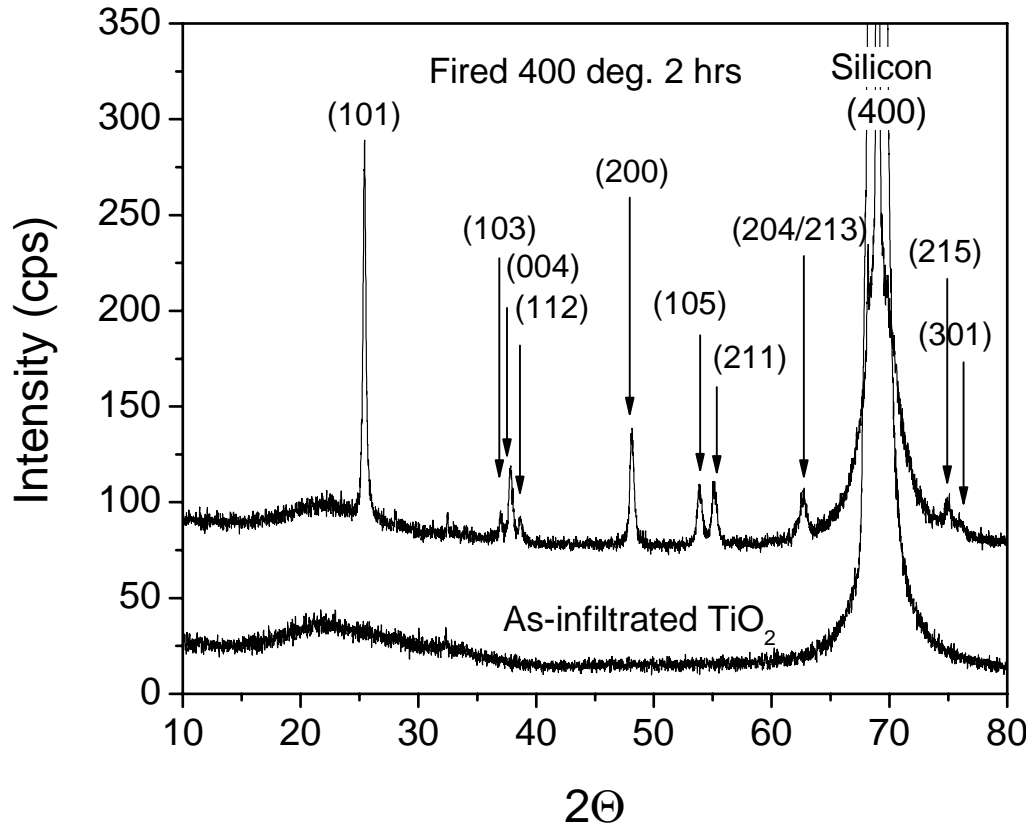


433 nm opal infiltrated
with TiO_2

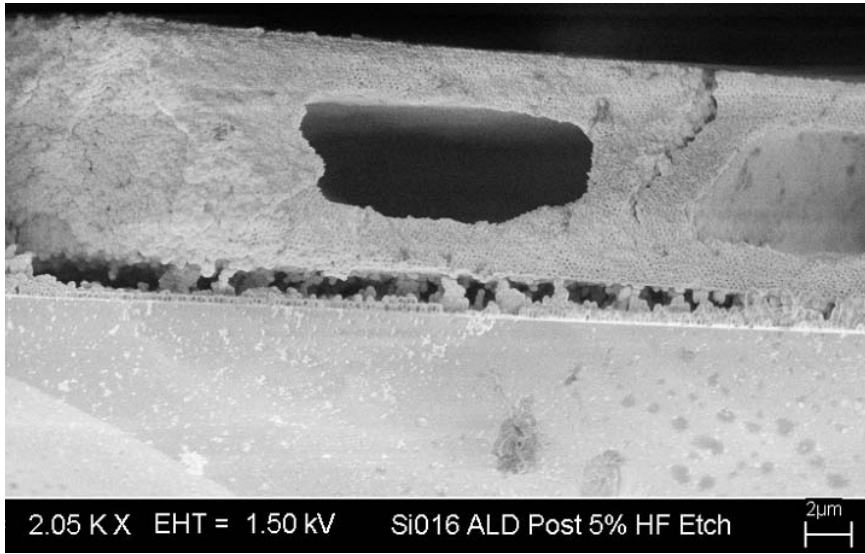


433 nm TiO_2 inverse opal

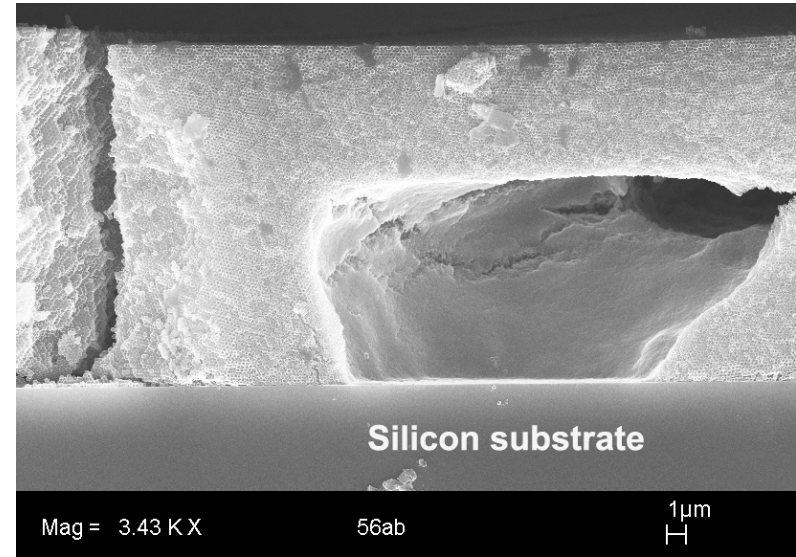
- TiO_2 infiltration at 100°C produces very smooth and conformal surface coatings with rms roughness $\sim 2\text{\AA}$.
- Heat treatment (400°C , 2 hrs.) of infiltrated opal converts it to anatase TiO_2 , increasing the refractive index from 2.35 to 2.65, with only a 2\AA increase in the rms surface roughness.



- XRD data for 100°C 433 nm infiltrated TiO₂ opal (lower curve), and same sample after 400°C 2 hour heat treatment (upper curve).



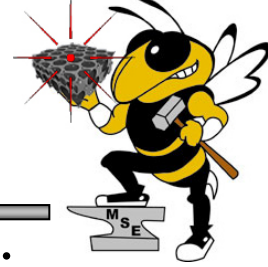
220 nm ZnS:Mn inverse opal



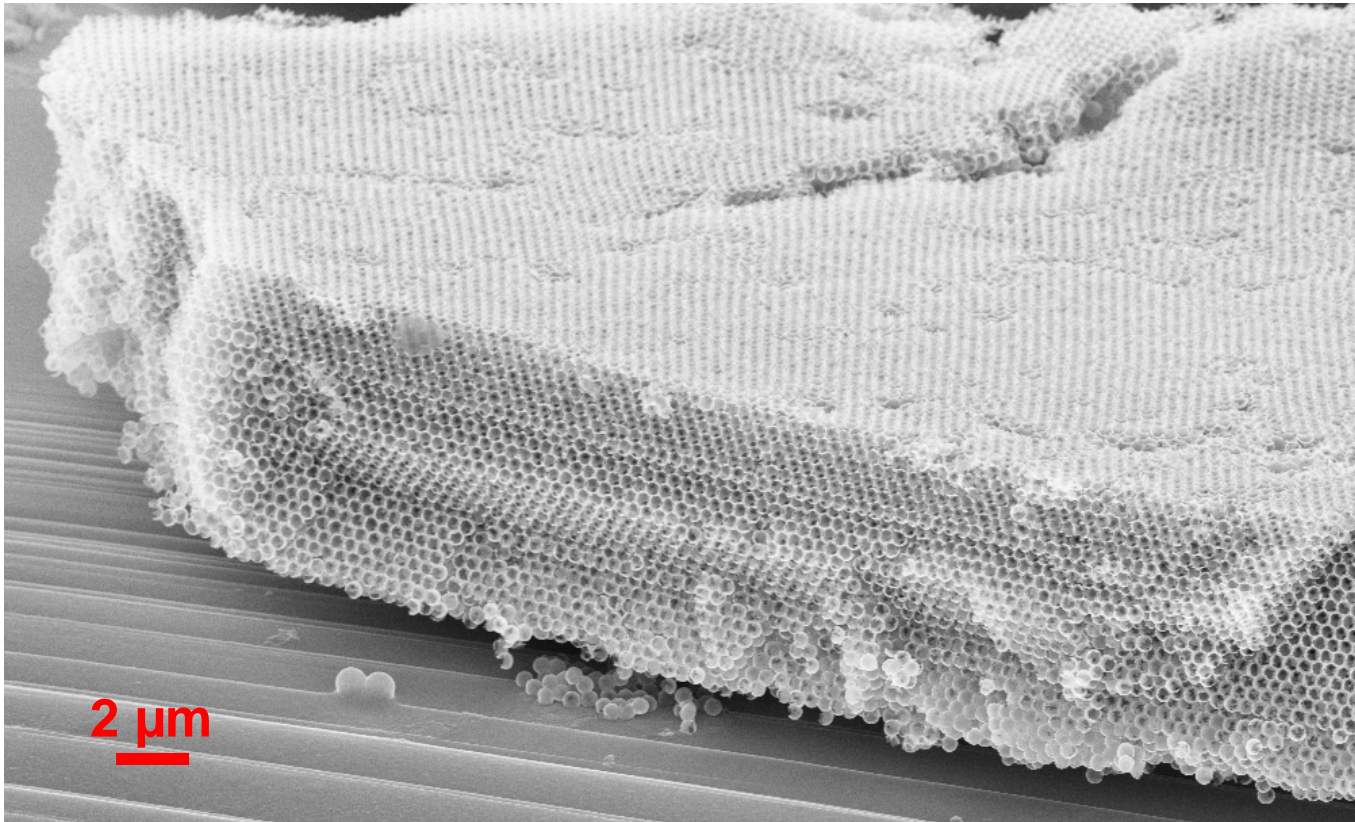
200 nm TiO₂ inverse opal

- For small opal sphere sizes, uniform infiltration becomes difficult creating air cavities when the opal is inverted.

Optimized TiO_2 Infiltration

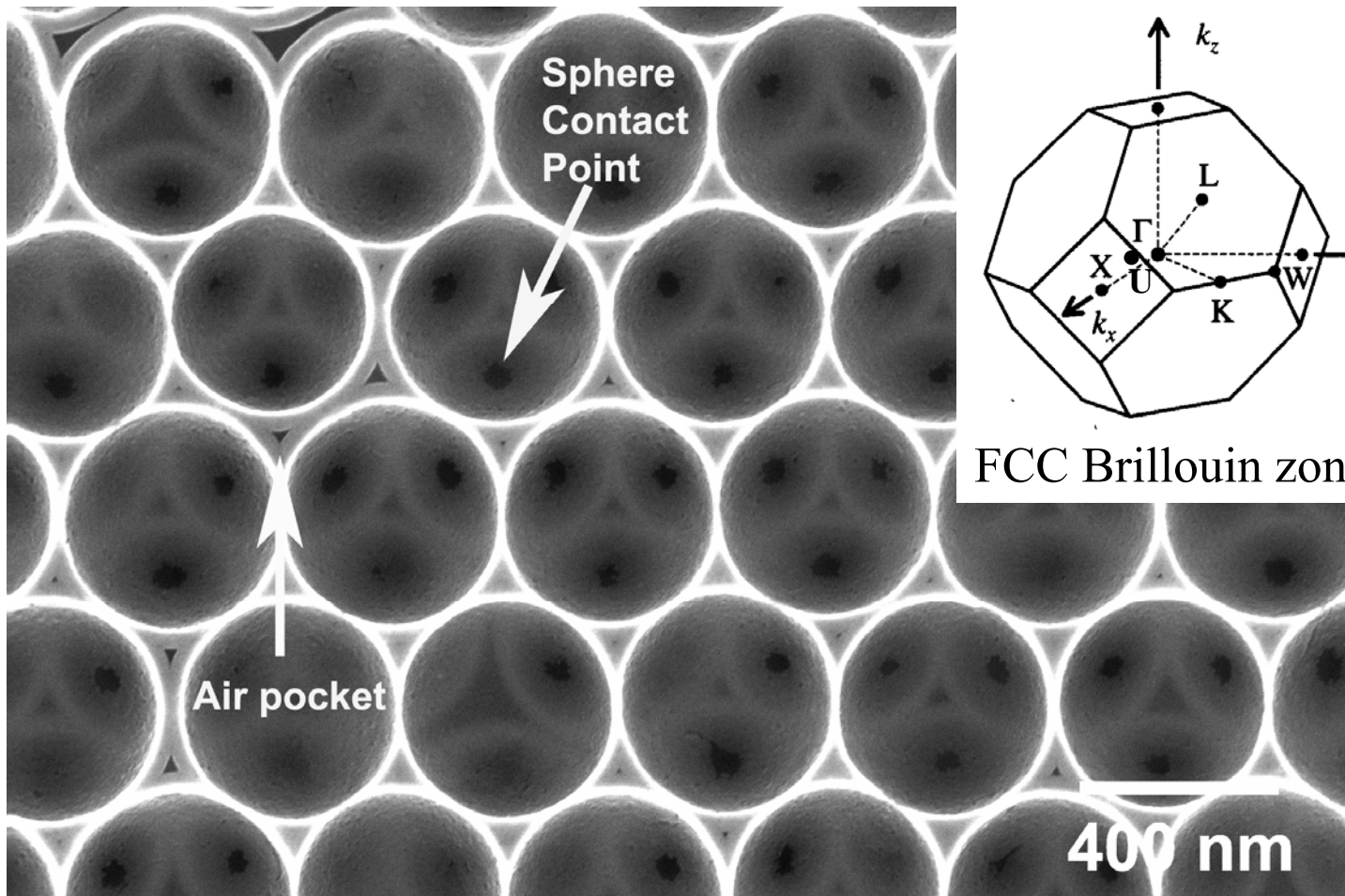


- Pulse and purge times were increased to optimize infiltration in opals with small sphere sizes.



433 nm TiO_2 inverse opal

Anatase TiO_2 Inverse Opal

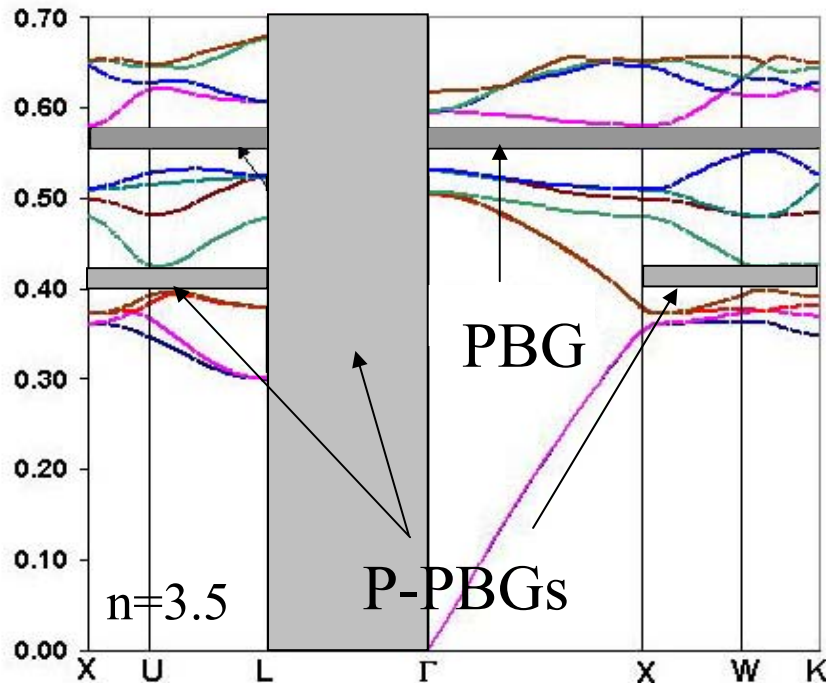


433 nm inverse opal, ion milled (111) surface

Inverse Opal Reflectivity: Theoretical Comparison

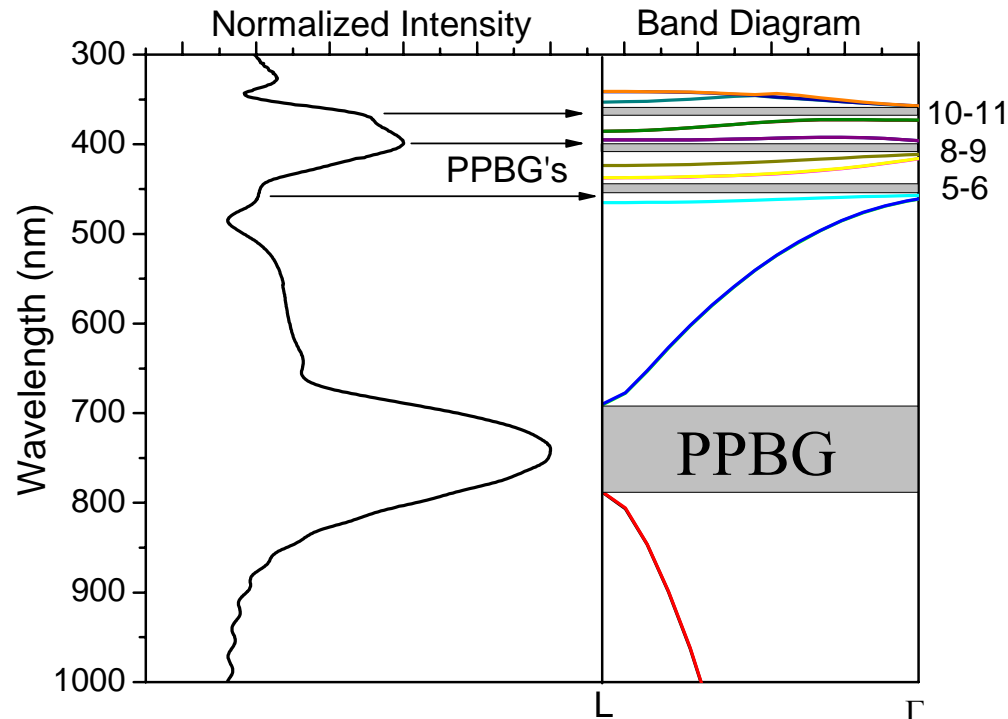


Silicon Inverse Opal Photonic Band Diagram



- Full PBG between bands 8 & 9
- PPBGs between other bands

TiO₂ Inverse Opal Reflectivity and Photonic Band Diagram

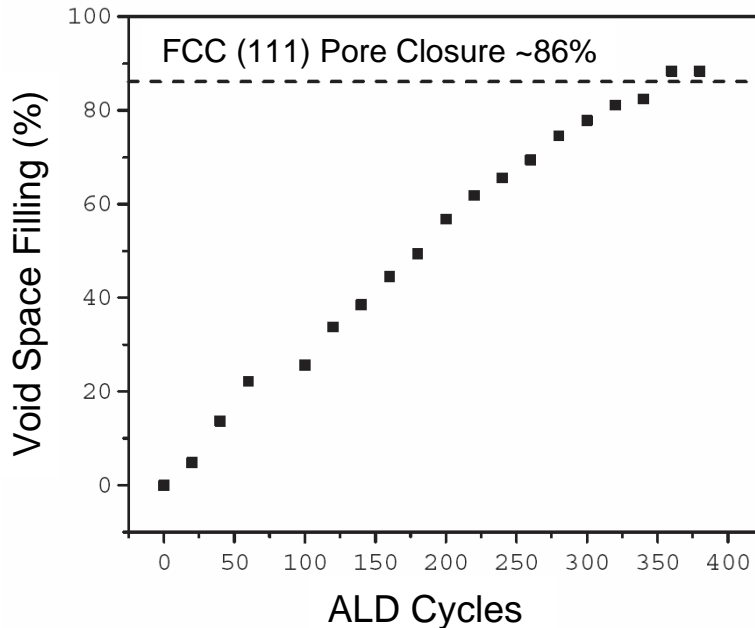


- 330 nm opal
- ~88% filling fraction
- 2.65 Refractive Index

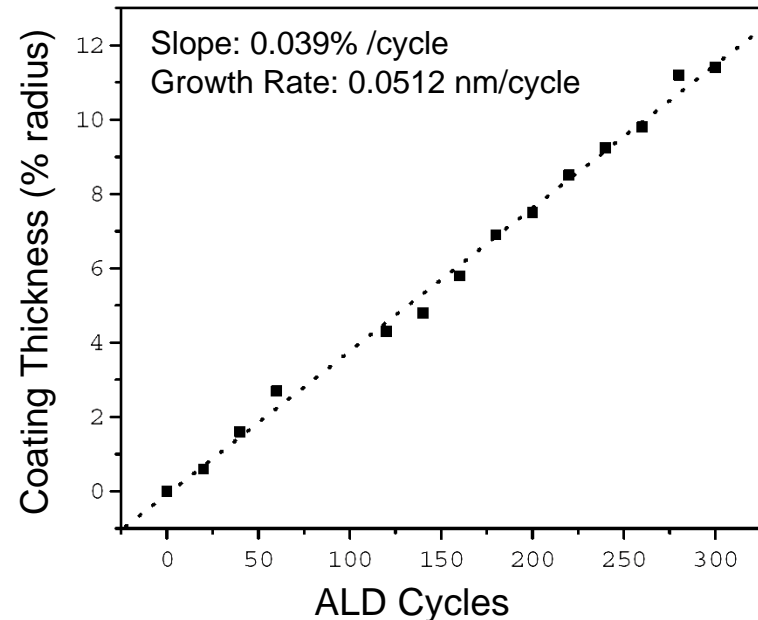
Precise Digital Opal Infiltration



Void filling fraction of opal as function of ALD Cycles calculated from reflectivity



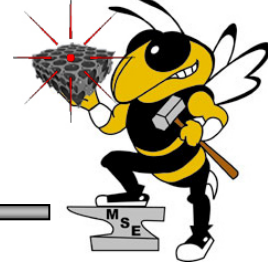
TiO₂ Coating Thickness as function of ALD cycles



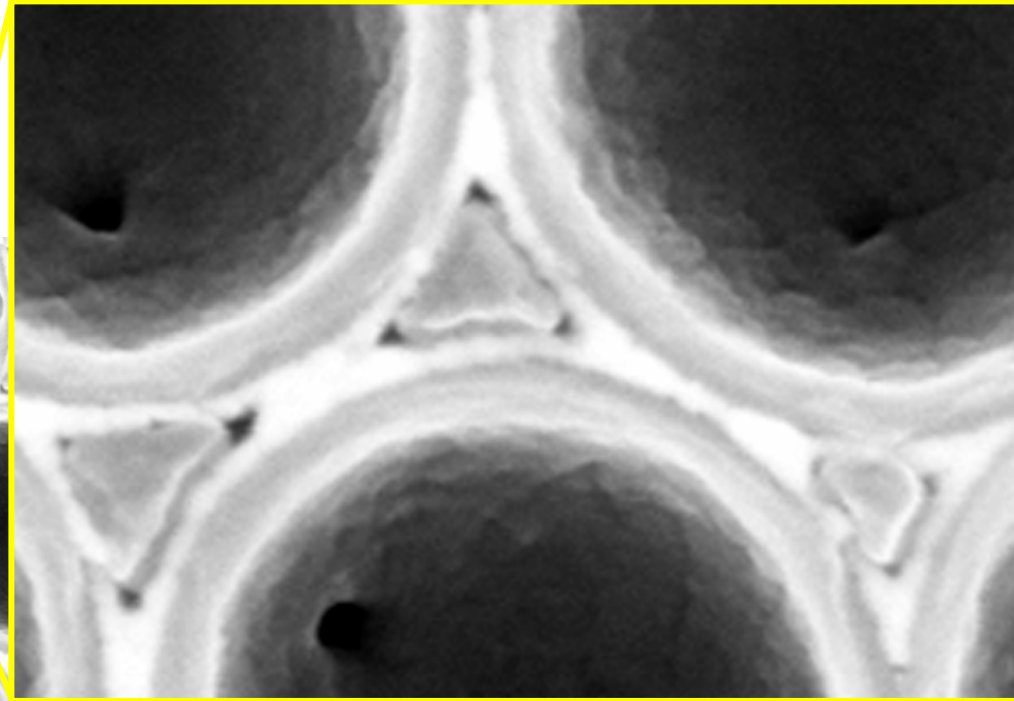
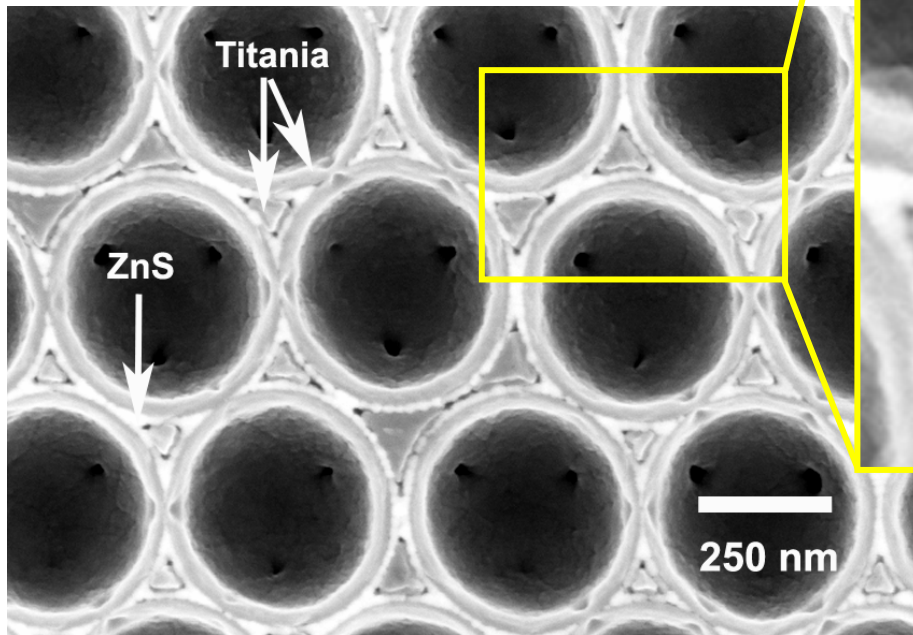
- **Optical verification of maximum filling fraction.**
- **ALD allows for ultra-fine control of opal infiltration.**

Multi-Layered Inverse Opal:

$\text{TiO}_2/\text{ZnS:Mn}/\text{TiO}_2$



- SEM of $\text{TiO}_2/\text{ZnS:Mn}/\text{TiO}_2$ inverse opal



330 nm sphere size

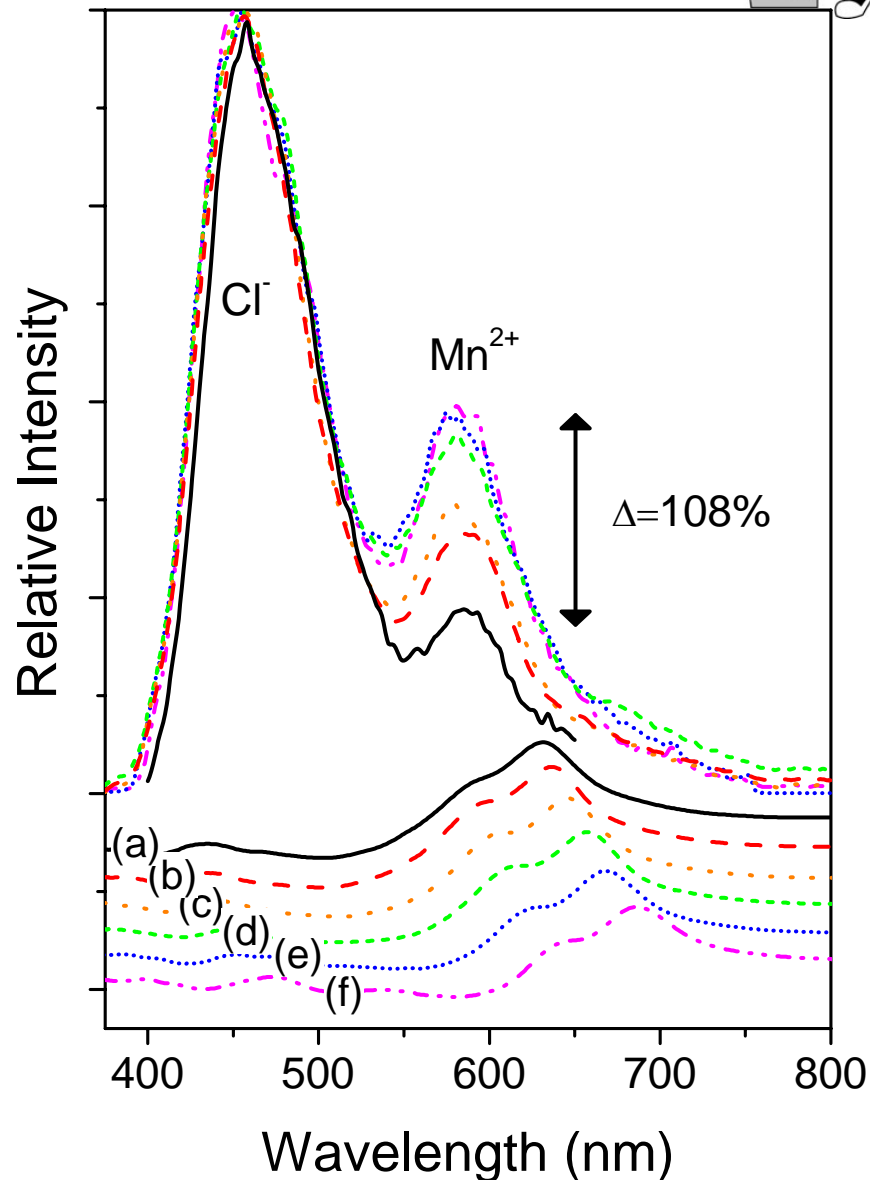
Luminescent multi-layered inverse opals
fabricated using ALD

Photoluminescence: ZnS:Mn/TiO₂ Composite



- 433 nm opal
- 337 nm N₂ laser excitation
- Detection normal to surface

- (a) 2-layer TiO₂/ZnS:Mn/air
(14 nm/20 nm) inverse opal
- (b-f) 3-layer TiO₂/ZnS:Mn/TiO₂
inverse opal after backfilling
with TiO₂ by
- (b) 1 nm
 - (c) 2 nm
 - (d) 3 nm
 - (e) 4 nm
 - (f) 5 nm



Summary



- Fabricated high quality inverse opal photonic crystals in the visible spectrum using ALD.
- TiO₂ ALD conditions optimized for complete, uniform infiltrations with smooth and conformal coatings.
 - Growth/Anneal protocol developed to form anatase inverse opals
- Precise control enables novel photonic crystal structures:
 - Inverse opals with void space air pockets (enhanced PBG)
 - Achieved maximum infiltration of 86%
 - Perfect match between reflectivity and calculated band structure
 - Multi-layered luminescent inverse opals
- Modification of photoluminescence by precise infiltration
 - Increased Mn²⁺ peak intensity by 108%
- **Pathway for photonic crystal band gap engineering.**

Acknowledgments



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